

Search Notes



Application/Control No.

09/677,401

Examiner

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Applicant(s)/Patent under Reexamination

KERN ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	8/05	Don
	7		
	8		
	9		
	10		
	14		
	26		
	35		
	36		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US Patent	8/05	Don
PG Pub Patent		
II FOREIGN		
III NPL		
1. Ftext ¹		
2. Ftext ²		
3. NFtext ³		